



The interior interfaces of a semiconductor/metal nanocomposite and their influence on its physical properties

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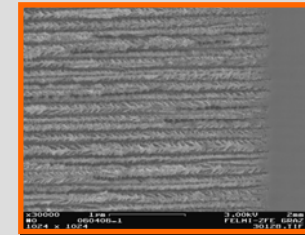


Talk, TNT 2008, Oviedo, Spain

Outline

- **PS-Matrix**

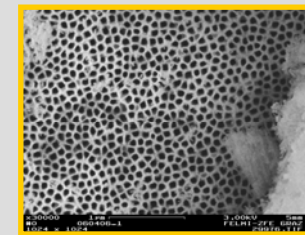
Fabrication of the PS matrix with a certain morphology



- **Structural characterization by SEM**

- **Nanocomposite system**

Metal-filling – ferromagnetic nanostructures

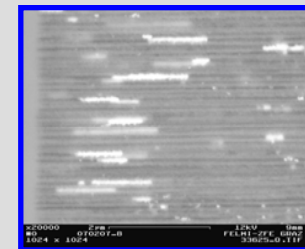


- **Specific physical properties due to nanostructuring**

- **Interface: Si/PS/metal**

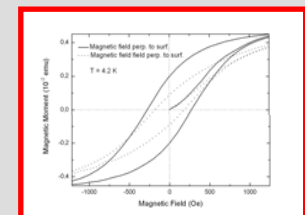
FTIR-investigations, Raman-spectroscopy

Magnetic characterization



- **Outlook**

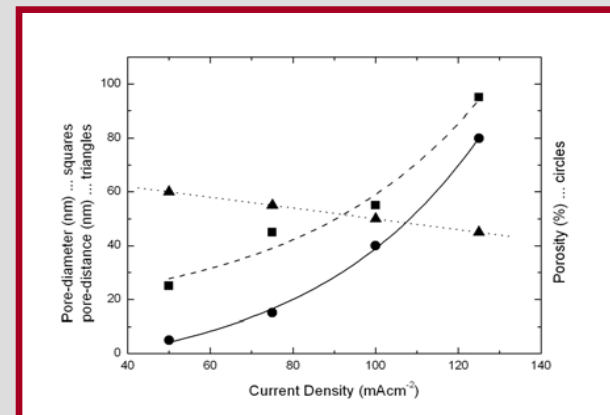
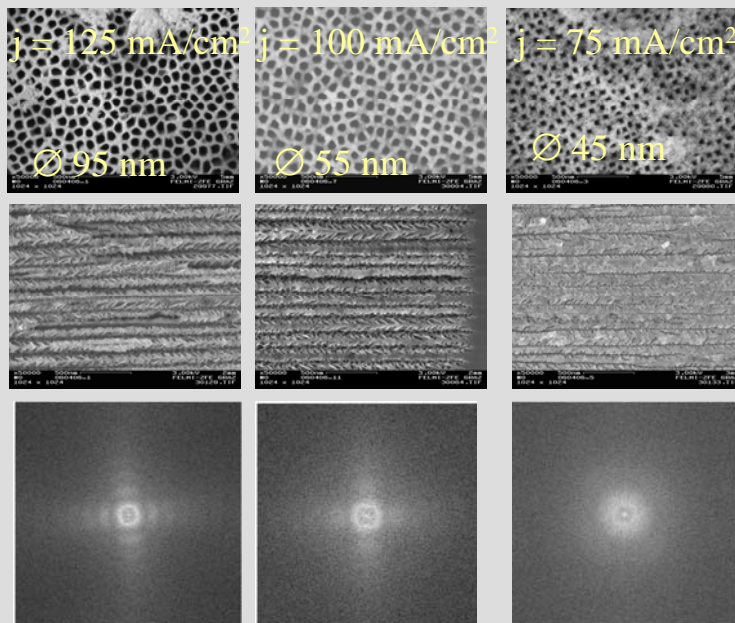
- **Conclusion**



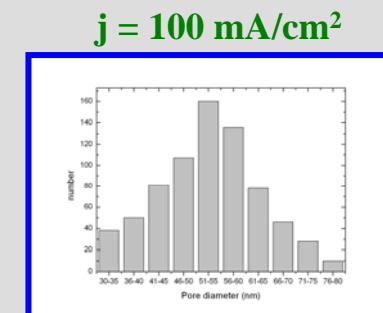
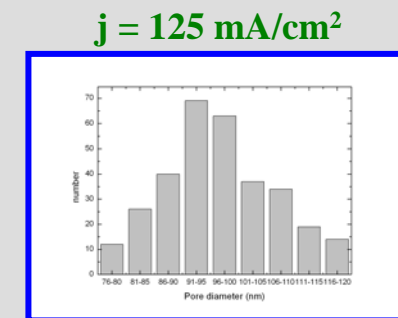
Fabrication of the PS-matrix

Aim: fabrication of mesoporous silicon templates by self-organization

Desired properties: defined morphology with:
 oriented, separated pores
 quasi-regular pore arrangement
 narrow pore-size distribution



Decreasing current density ($j < 75 \text{ mA/cm}^2$) – more and more random pore distribution



Metal-deposition – ferromagnetic nanostructures



Metal-filling of the PS-template by electrochemical deposition

Typical used deposition parameters

Current density j [mA/cm ²]	Pulse duration t_{pulse} [s]
10	20
20	20
50	10
50	5

Used electrolytes

NiCl₂ – solution: 170 g/l NiCl₂
40 g/l H₃BO₃

Watts-electrolyt: 45 g/l NiCl₂
300 g/l NiSO₄
45 g/l H₃BO₃

CoSO₄ – solution: 120 g/l NiCl₂
30 g/l H₃BO₃

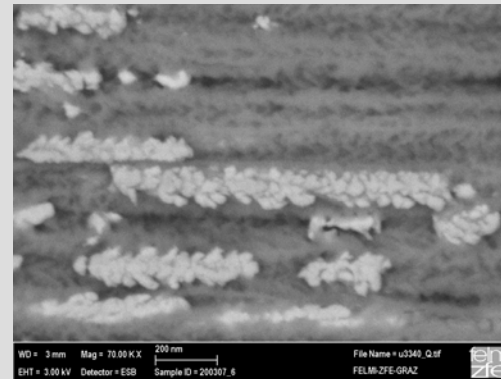
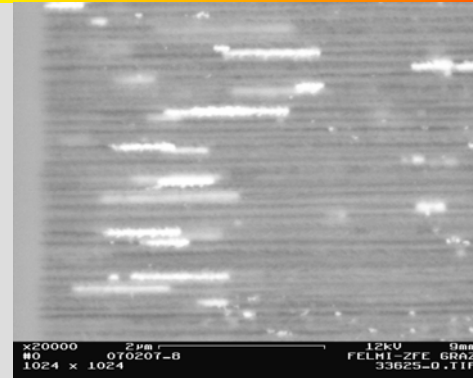
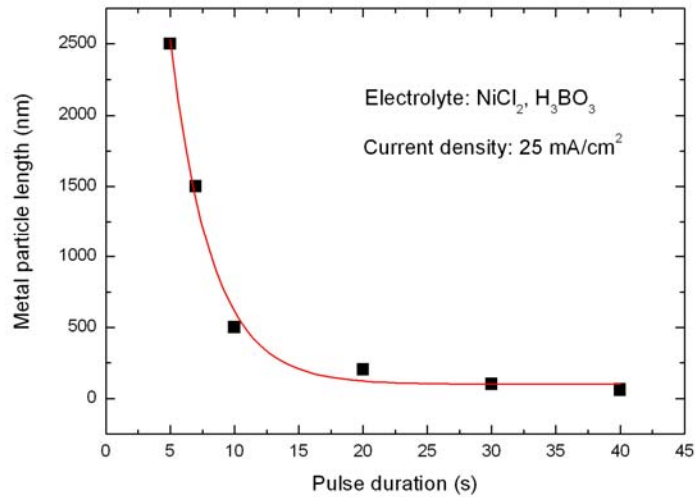
Metal filling of the channels depends on the process-parameters

Various metals precipitate differently under similar deposition conditions

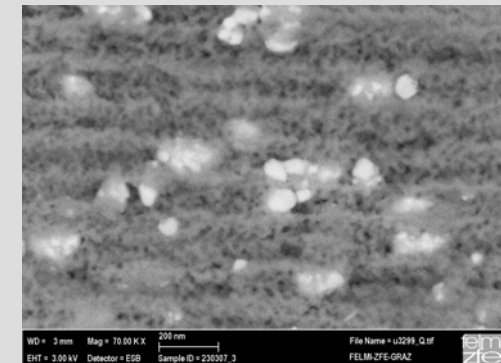
Structural characterization of the nanocomposite

Precipitated Ni-structures

With decreasing pulse duration the elongation of the precipitated nanostructures increases

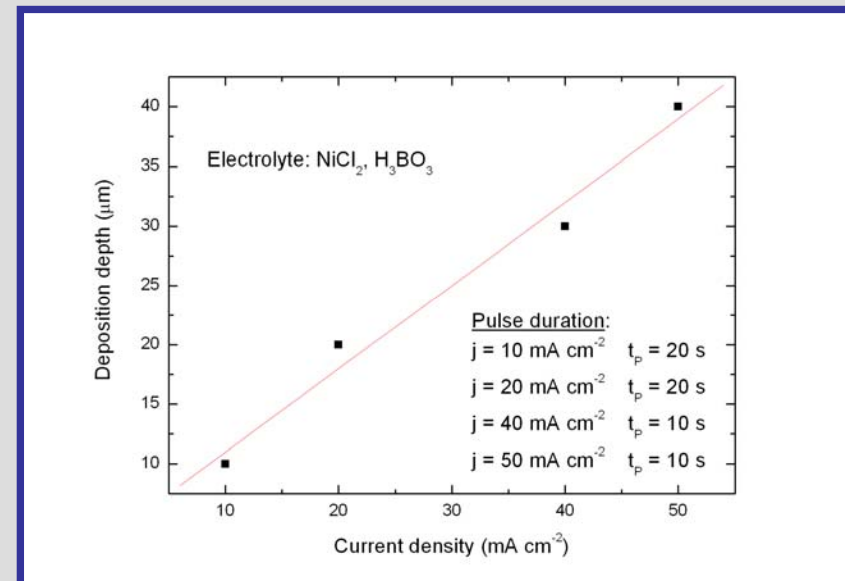
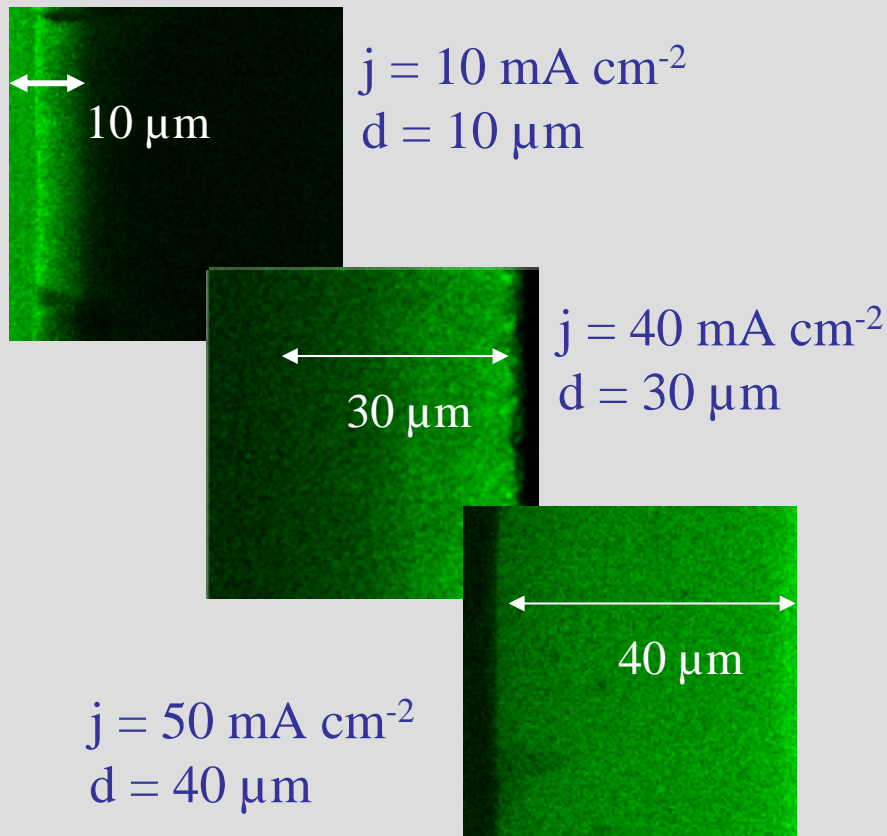


$t_p = 40 \text{ s}$
 $l = 60 \text{ nm}$



EDX spectroscopy - element distribution

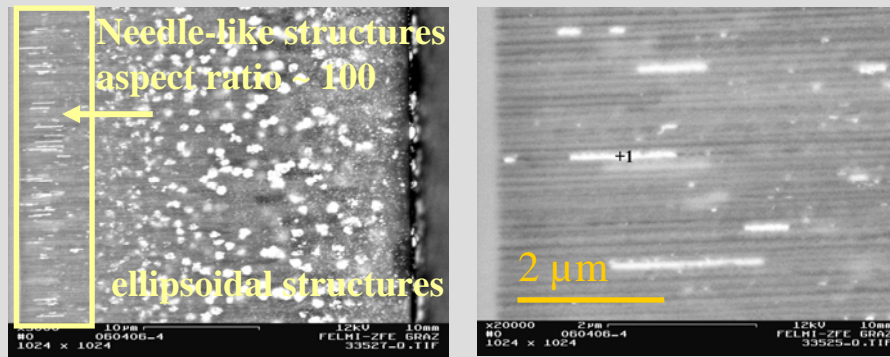
Spatial Ni-distributions



Relation between current density and deposition depth

Embedded metal-structures

Embedded Ni-wires

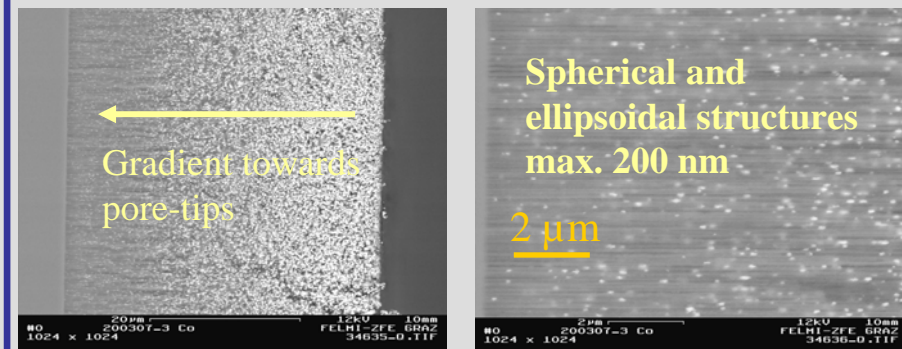


Deposited Ni within the pores shows a distribution between spherical and elongated particles.

Elongated Ni-particles with a length of about 2 μm and a diameter of 50 nm (**aspect ratio 40**).

PS-channels: aspect ratio ~ 1000

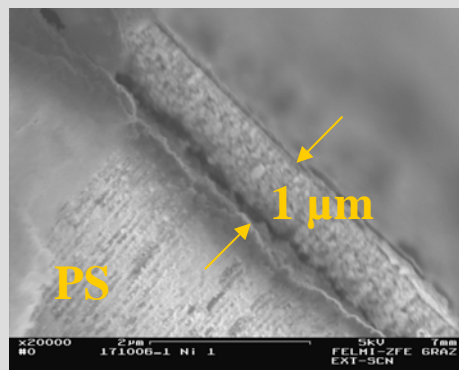
Embedded Co-particles



Gradient of the Co concentration with increasing pore length.

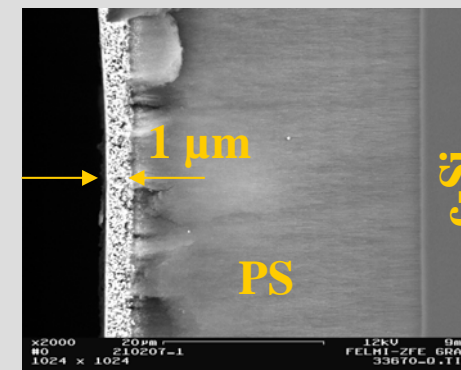
The size of the precipitated Co-particles is in the range of a few hundred nm. The filling is achieved down to the pore tips.

Deposited Ni-layer



⇒ Of interest for coming transport measurements

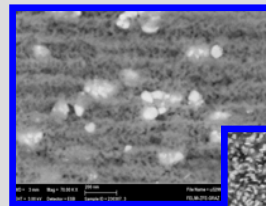
Deposited Co-layer



Nanosystem – particles / wires

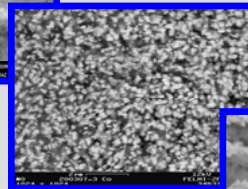
Ferromagnetic nanosystem with tailored metal structures:

Spheres



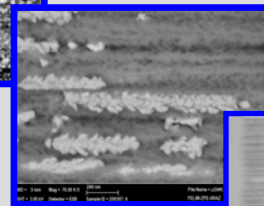
1 ~ 60 nm

Ellipsoids



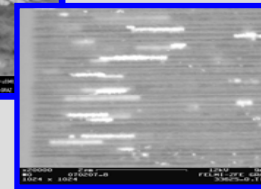
1 ~ 200 nm

Elongated particles

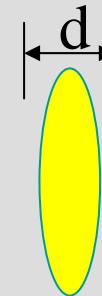
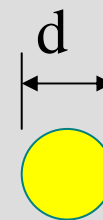


1 ~ 500 nm

Wires



1 ~ 2 μm



Magnetic properties of such ferromagnetic nanoparticles mainly depend on their size and shape

Properties of the whole system are determined by the distribution of the structures and their mutual arrangement

⇒ Magnetic properties tunable by process parameters

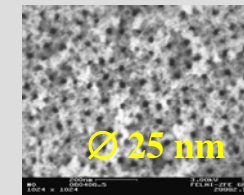
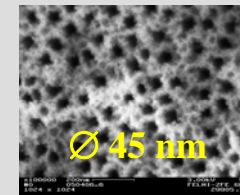
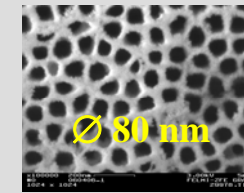
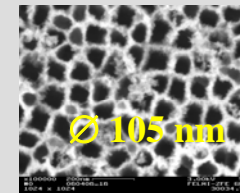
Distribution of the magnetic nanostructures

Modification of the PS-templates

⇒ influence on the magnetic interactions

⇒ Different interactions of the particles:

- Dipolar interaction
- Exchange interaction - RKKY-interaction
- Interaction by tunnelling through barriers



⇒ **Complex system with tunable properties**

Specific physical properties due to nanostructuring



- **Silicon \Rightarrow PS:** optical properties change due to QC-effects
the properties are influenced by oxidation
(*L. Canham, Appl. Phys. Lett. 57, 1990, 1046*)
- **Metal nanostructures:** magnetic behaviour – change from
multi domain to single domain behaviour
oxidation of particles – exchange bias effect
(if the metal-oxide is AFM)
(*J. Nogues, et al. Physics Reports 422, 2005, 65-117*)

Knowledge about interface important

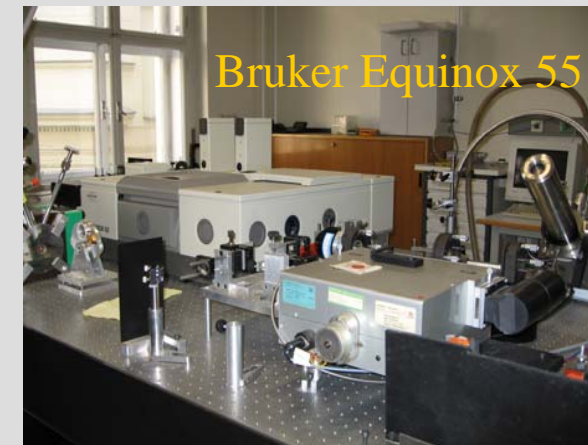
Interface



Optical characterization is carried out by FTIR-spectroscopy

FTIR-magnetometer: Bruker Equinox 55

Raman-spectroscopy



Structural characterization

SEM-, TEM-images

Magnetization measurements performed by SQUID-magnetometry

SQUID-magnetometer: Quantum Design MPMS XL7

Field range: ± 7 T

Temperature range: 1.7 K – 360 K

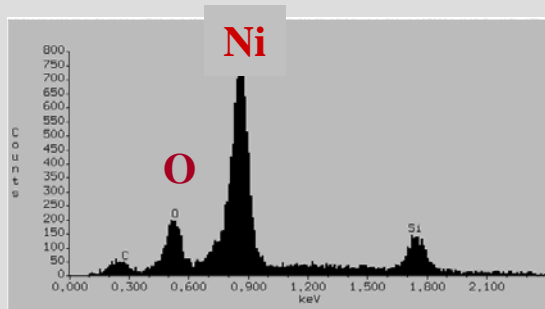
Resolution: $5 \cdot 10^{-9}$ emu



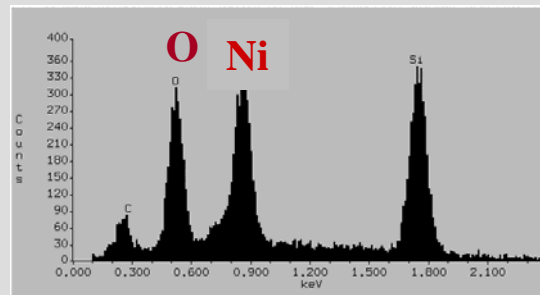
SEM – EDX spectroscopy

EDX-Spectroscopy

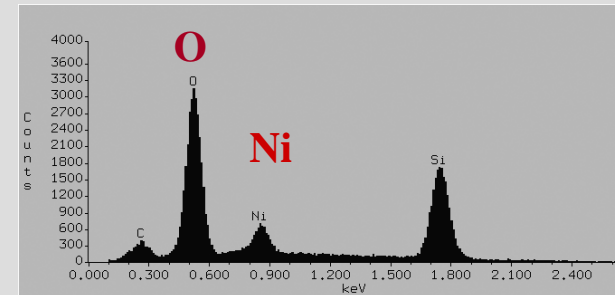
1



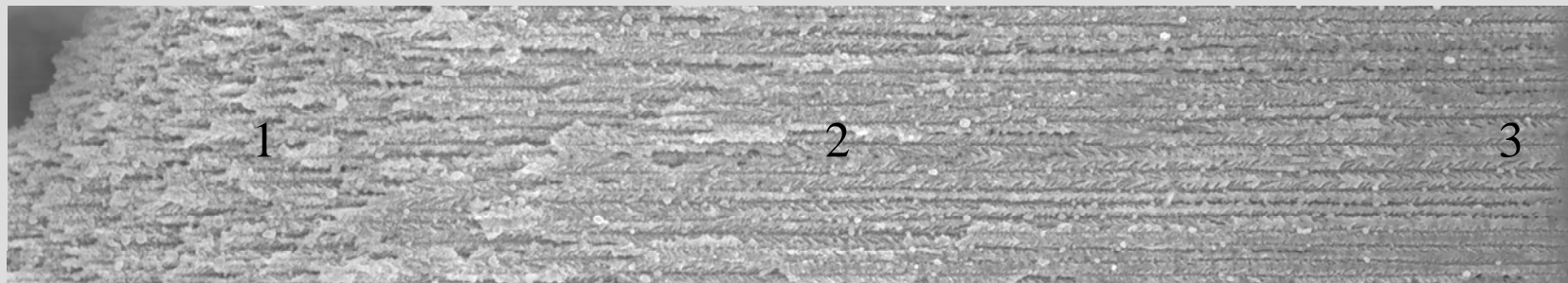
2



3



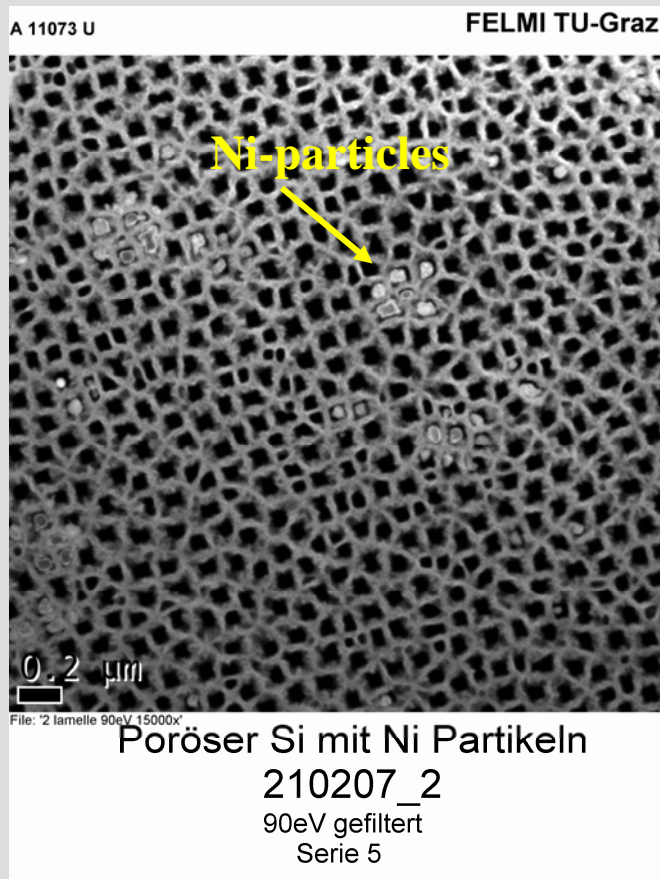
EDX-Spectra, 3keV



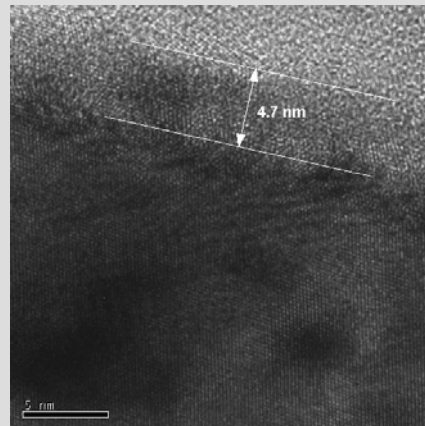
Ni-distribution is in good agreement with the pore length;
The estimated oxygen content is due to SiO_2

TEM-images of FIB cut sample

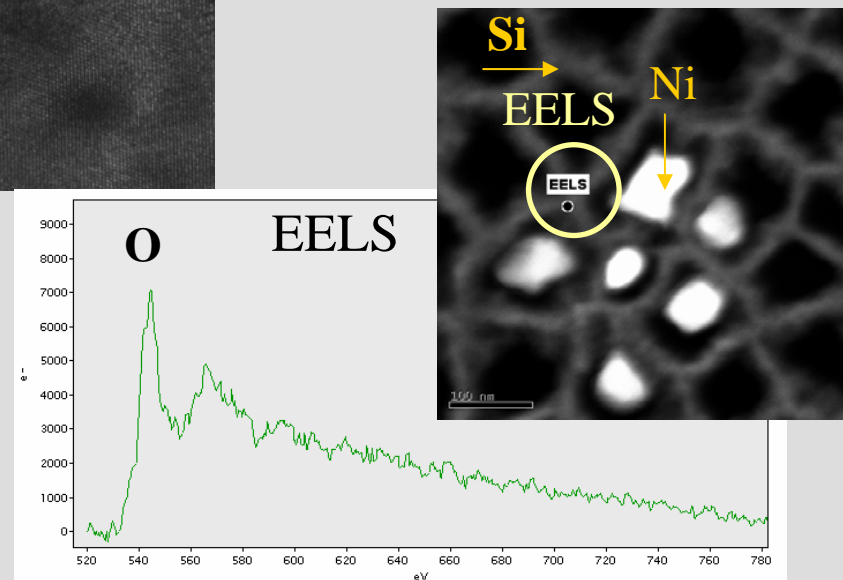
Ni-filled PS-specimen cut by FIB



Top view-image showing the Ni-filled pores

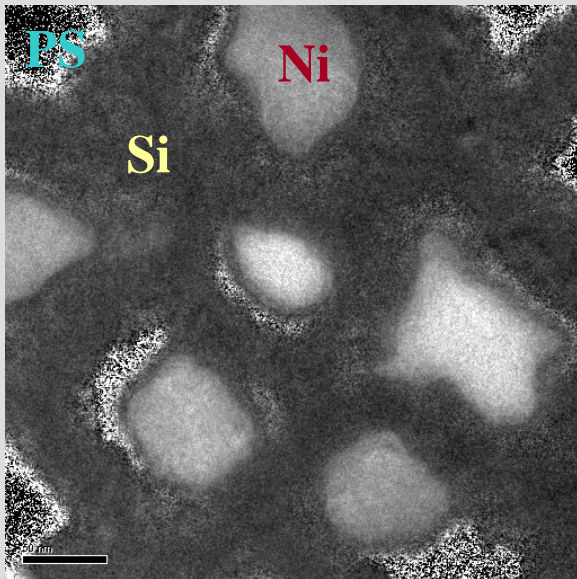


Interior surface of the PS-templated Si

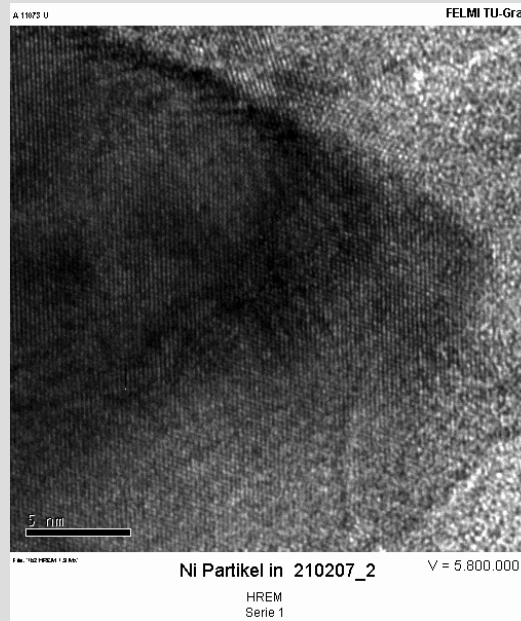


HRTEM – crystalline orientation

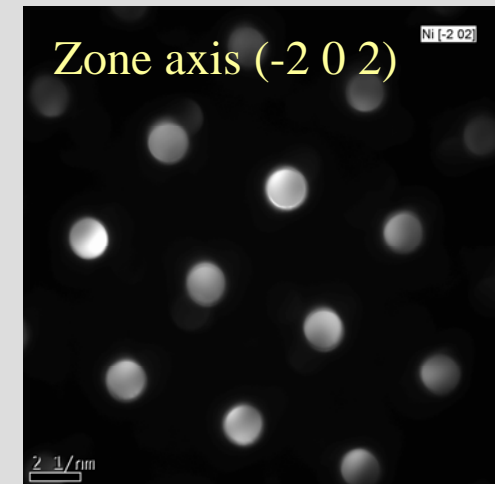
Ni-particles within pores



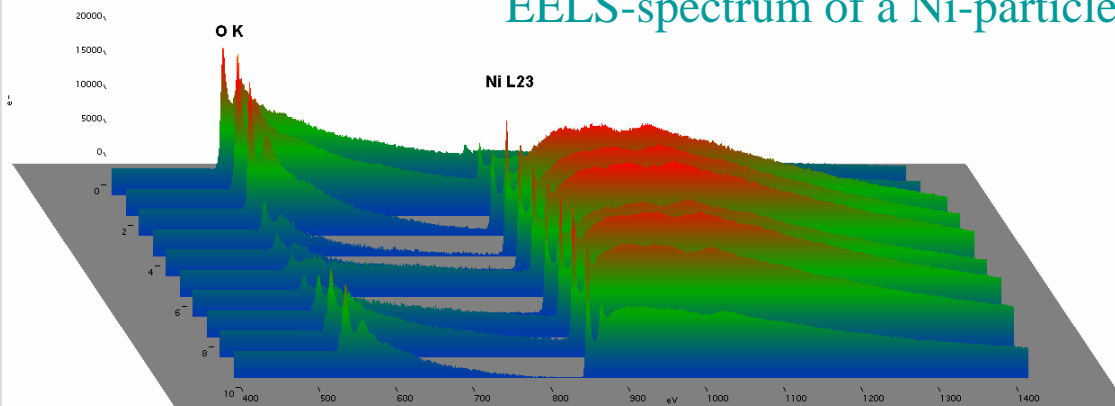
HRTEM of a Ni-particle



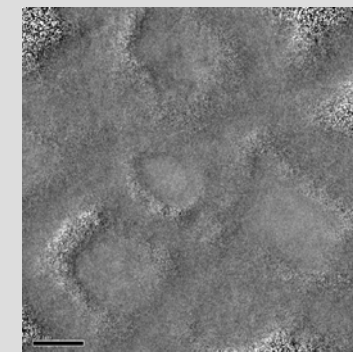
Crystalline orientation of a Ni-particle



EELS-spectrum of a Ni-particle



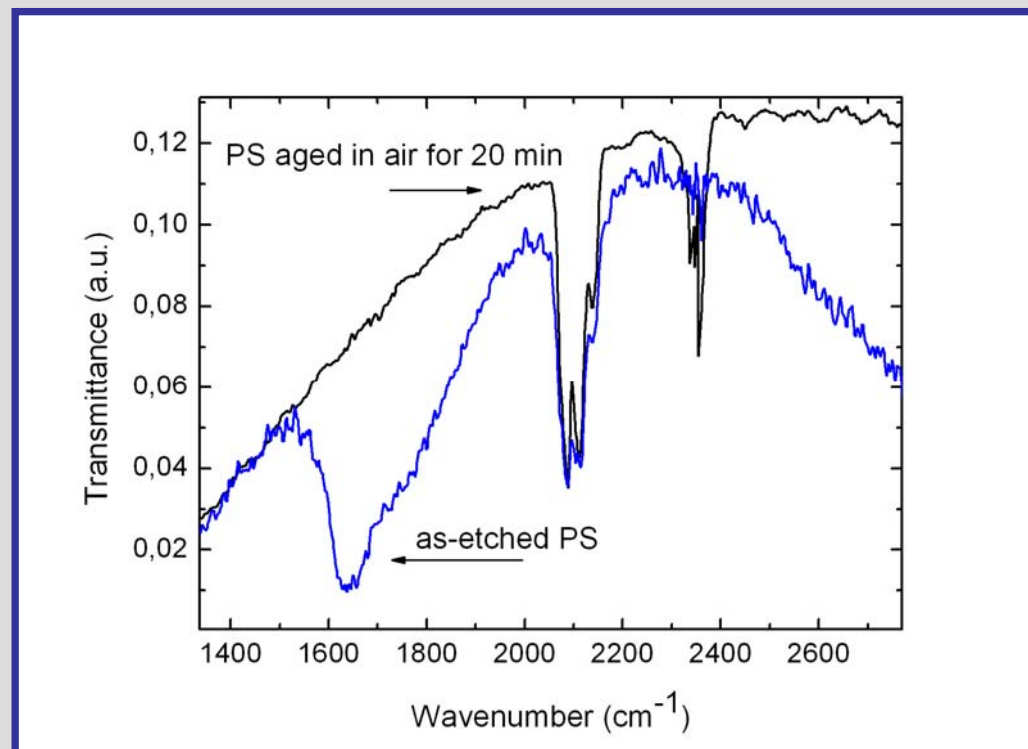
Oxide distribution



Optical behaviour

FTIR-investigations

Comparison between as-etched PS and aged PS



Si-H vibration modes:

2087 cm⁻¹: Si₂-Si-H₂
stretching mode

2115 cm⁻¹: Si₃-Si-H
stretching mode

2138 cm⁻¹: Si₂-Si-H
stretching mode

O-Si-H modes:

2250 cm⁻¹

Si-OH modes:

1635 cm⁻¹

FTIR-investigations of metal filled samples

Comparison between Ni and Co filled specimens

2200 cm^{-1} and 2250 cm^{-1} :
O-Si-H modes

1635 cm^{-1} : Si-OH

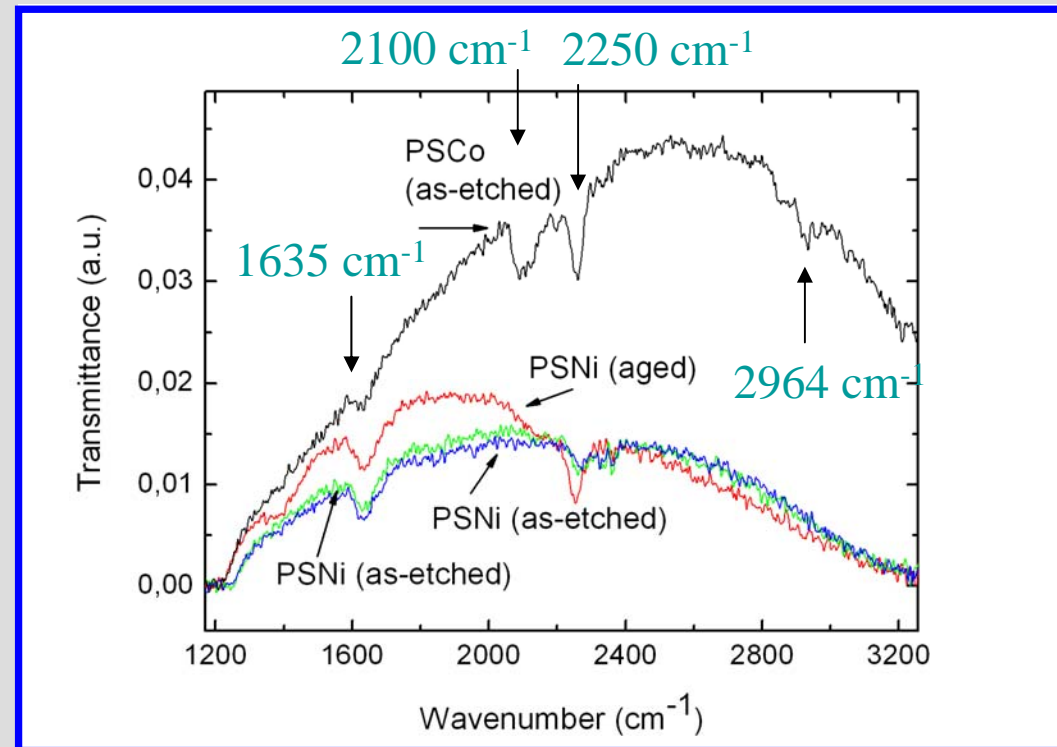
Co-loaded sample:

~ 2100 cm^{-1} : SiH-modes

2964 cm^{-1} : SiO_x modifications

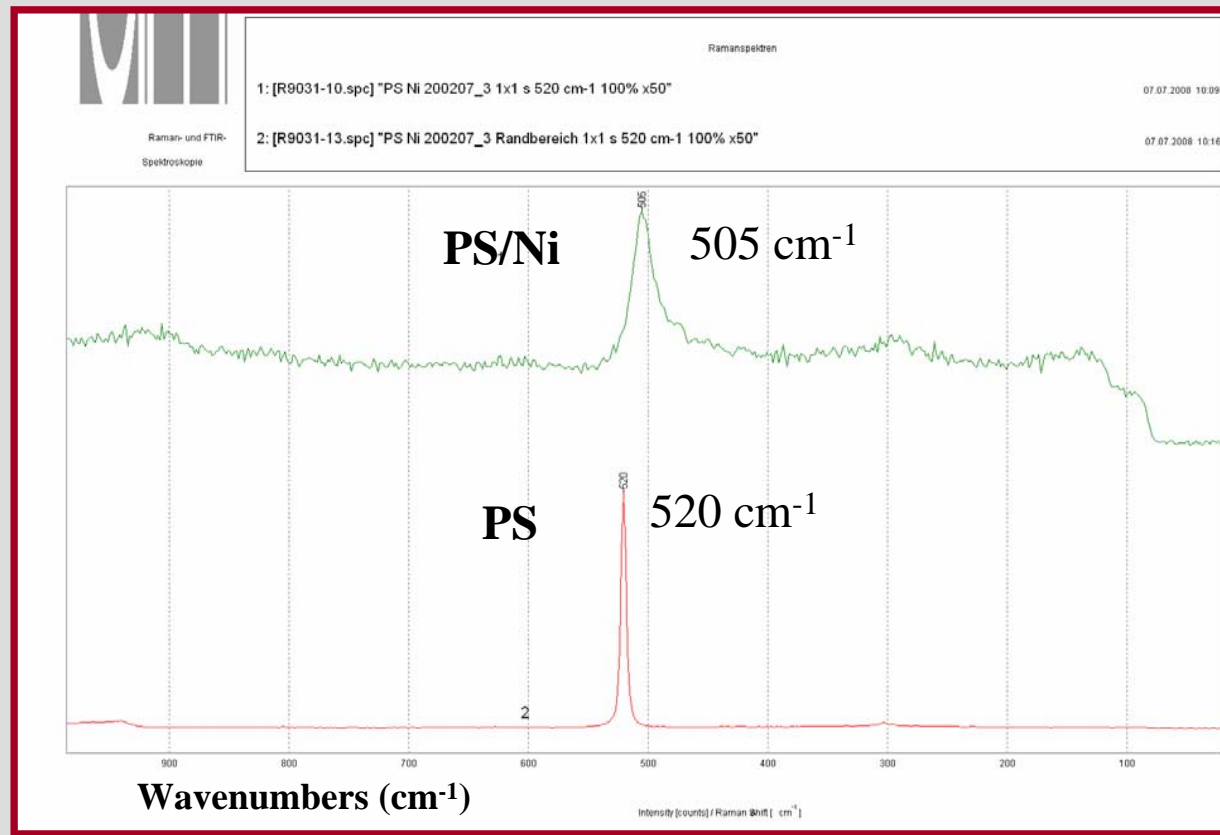
Ni-loaded sample:

1368 cm^{-1} . SiO_3



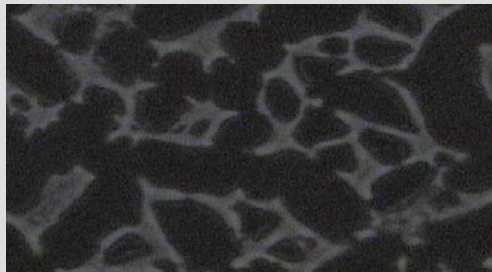
Raman-spectroscopy

Comparison between bare PS and Ni-filled PS



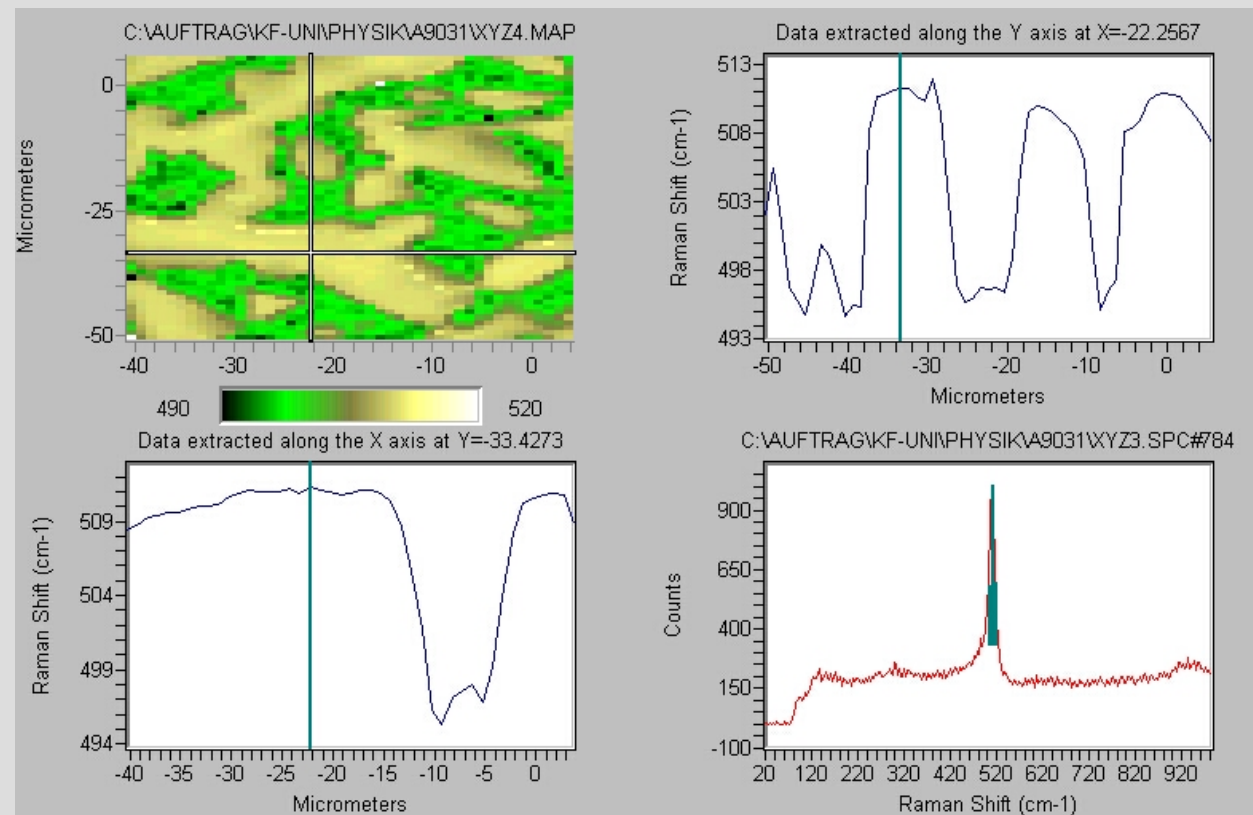
Shift of the Raman peak of PS/Ni to lower wavenumbers caused by stress

Raman-mapping

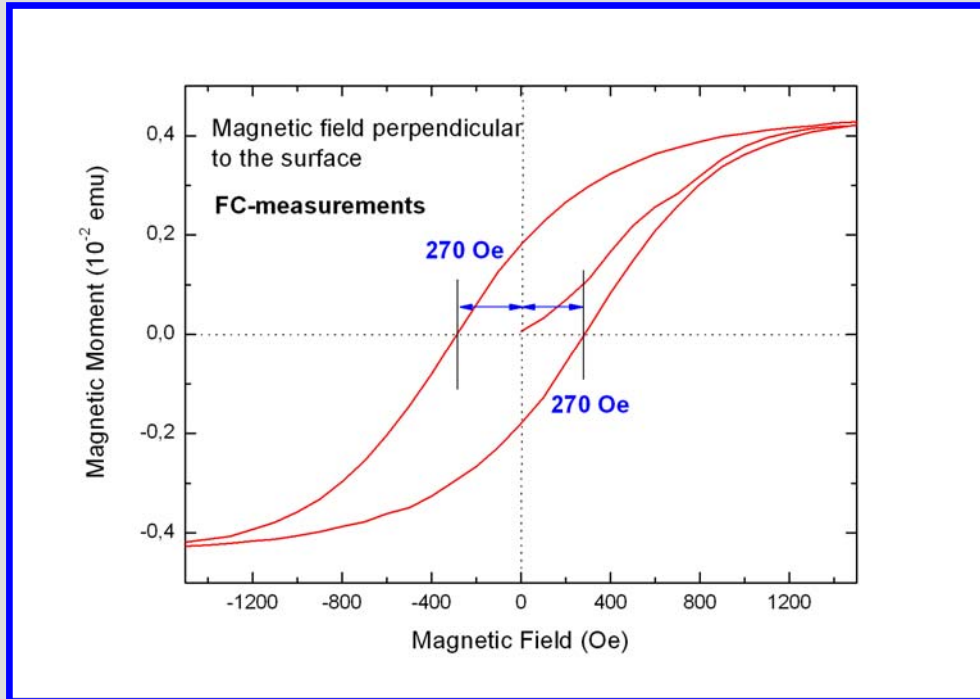


Micrograph of a PS/Ni sample

Raman mapping of the area shown beside:
Green: Ni-loaded regions – shift of the Raman peak due to higher stress
Yellow: silicon



Magnetization measurements



Proof of an oxide shell

Symmetrical coercivity ($H_C = 270$ Oe) obtained from field cooled measurements indicates that the metal particles are not covered by an antiferromagnetic oxide layer

Due to field cooled measurements exchange bias effects can be excluded.

Perspectives and ideas for future work



- **Control of oxide growth during electrodeposition**
- **High quality oxide layer as tunnel barrier for spin-injection into silicon**
- **Transport measurements**
(magnetic field parallel and perpendicular to the surface, respectively)

Conclusion



- Effective method to achieve a quasi-regular PS template in the meso-/macro porous regime without lithography.
- The oriented pores show a quite homogeneous pore distribution which shows a quadratic-like symmetry for special preparation conditions.
- This PS template is used for filling with a ferromagnetic metal to obtain 3-dim nanostructure arrays with tunable magnetic properties.
- This nanocomposite system gives rise to applications in sensor technology, magneto-optical devices but also to detect spin-injection into Si. Promising candidate for silicon based spintronic devices.

Coworkers



H. Krenn



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P. Granitzer



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**THANK YOU FOR
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